



PATENT APPLICATION
ATTORNEY DOCKET NO. 5038-340

IN THE
UNITED STATES PATENT AND TRADEMARK OFFICE

Inventors: Pete D. Vogt
Serial No.: 10/714,026 Examiner: unknown
Filing Date: November 14, 2003 Group Art Unit: 2186
Title: BIT LANE TESTING WITH VARIABLE MAPPING

INFORMATION DISCLOSURE CITATION
FORM PTO-1449 (Modified)

U.S. PATENT DOCUMENTS

Exam Init	Ref	Document Number	Issue Date	Name	Class	Sub Class
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Exam Init	Ref	Document Number	Publication Date	Country	Name
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Examiner: /John J. Tabone Jr/ (05/08/2006)
Date Considered: _____



PATENT APPLICATION
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IN THE
UNITED STATES PATENT AND TRADEMARK OFFICE

Inventors: Pete D. Vogt

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Group Art Unit: 2186

Title: LANE TESTING WITH VARIABLE MAPPING

SUPPLEMENTAL INFORMATION DISCLOSURE CITATION
FORM PTO-1449 (Modified)

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